

Analysis of a test method for delay faults in NoC interconnects

Bengtsson, Tomas; **Jutman, Artur**; Kumar, Shashi; **Ubar, Raimund-Johannes**; Peng, Zebo Proceedings of the IEEE East-West Design & Test Workshop (EWDTW'06) : Sochi, Russia, September 15-19, 2006 2006 / p. 42-46 : ill

Computer aided design support of FSM multiplicative decomposition

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How to emulate Network-on-Chip?

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